


<b>Search Notes</b> 	<b>Application/Control No.</b> 10517214	<b>Applicant(s)/Patent Under Reexamination</b> MAEKAWA ET AL.
	<b>Examiner</b> Jaisle, Cecilia M	<b>Art Unit</b> 1624

SEARCHED			
Class	Subclass	Date	Examiner
514	403, 404	3/10/2009	Cecilia Jaisle
548	373.1, 375.1	3/10/2009	Cecilia Jaisle
546	275.4, 276.4	3/10/2009	C. Jaisle
544	238	3/10/2009	CJ

SEARCH NOTES		
Search Notes	Date	Examiner
STN and Inventor Names searched by STIC	10/10/2007	Cecilia Jaisle

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
514	403, 404	3/10/2009	C. Jaisle
548	373.1, 375.1	3/10/2009	C. Jaisle
546	275.4, 276.4	3/10/2009	CJ
544	238	3/10/2009	CJ

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